

BS EN 62047-26:2016



BSI Standards Publication

Semiconductor devices — Micro-electromechanical devices

Part 26: Description and measurement
methods for micro trench and needle
structures

National foreword

This British Standard is the UK implementation of EN 62047-26:2016.

The UK participation in its preparation was entrusted to Technical Committee EPL/47, Semiconductors.

A list of organizations represented on this committee can be obtained on request to its secretary.

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